## AMENDMENTS TO THE CLAIMS

- 1. (Canceled)
- 2. (Currently amended) The method of claim 1 wherein the voltage is varied

  A method of controlling the burning in of at least one I/C chip in a burn in tool, wherein

  said tool has a device for mounting each chip to be burned in, a power source to supply electrical

  current to burn in each chip, and a monitor to continuously monitor the temperature value of each

  chip, comprising the steps of:

  continuously monitoring at least one electrical value input to each chip selected from the

  group of current, voltage and power, and varying the voltage to maintain the current value below

  a given value.
- A method of controlling the burning in of at least one I/C chip in a burn in tool, wherein said tool has a device for mounting each chip to be burned in, a power source to supply electrical current to burn in each chip, and a monitor to continuously monitor the temperature value of each chip, comprising the steps of:

  continuously monitoring at least one electrical value input to each chip selected from the group of current, voltage and power, and varying the voltage to maintain the power value below a

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given value.

4-7 (Canceled)

	8.	(Currently amended)	The tool of claim 7 wherein the voltage is varied A
<u>burn i</u>	n tool	for burning in at least one I/C	Chip comprising:
	a str	ucture for mounting each chi	p to be burned in:
	a po	wer source to supply electric	al current to burn in each chip:
	a str	ucture for continuously moni	toring at least one electrical value input to each chip
selecte	ed fron	the group of current, voltag	e and power, and
<del> </del>	a stru	cture to vary the voltage to n	naintain the current value below a given value.
	9.	(Currently amended)	The tool of claim 5 wherein the voltage is varied A
burn is	1 tool f	for burning in at least one I/C	chip comprising:
	a stri	acture for mounting each chip	o to be burned in:
a power source to supply electrical current to burn in each chip;			
a structure for continuously monitoring at least one electrical value input to each chip			
selecte	d from	the group of current, voltag	e and power, and
	a stru	cture to vary the voltage to m	naintain the power value below a given value.
	10 – 1	(Canceled)	